

What is claimed is:

1 1. A method of testing a semiconductor device having a memory, comprising:
2 selecting a portion of said memory;
3 testing said selected portion of said memory;
4 designating said selected portion of said memory as a designated memory
5 in response to an acceptable testing result; and
6 storing data in said designated portion of said memory for retrieval at a
7 later time.

1 2. The method of claim 1, further including attempting a soft repair of said
2 selected memory portion in response to an unacceptable test result and designating said
3 selected portion of memory in response to a successful repair.

1 3. The method of claim 2, further including selecting and testing additional
2 memory portions of said memory in response to an unacceptable test result and
3 unsuccessful repair attempt until a portion of said memory having an acceptable test
4 result or successful repair is found.

1 4. The method of claim 1, wherein said selected portion of memory is selected to
2 have a sufficient word length and number of bits for storing said data.

1 5. The method of claim 1, further including compressing said data before storing
2 said data in said designated portion of said memory.

1 6. The method of claim 5, further including decompressing said data after
2 retrieving said data from said designated portion of said memory.

1 7. The method of claim 1, wherein said data comprises bitmaps, memory fail data,
2 LBIST pass/fail signatures or pass/fail data.

1 8. The method of claim 1, further including sending said data to a tester.

1 9. The method of claim 1, wherein said data is generated by ABIST or LBIST.

1 10. A method of testing a semiconductor device having a memory, comprising:
2 providing a designated memory;
3 performing ABIST on a memory segment to generate memory test data;
4 storing said memory test data in said designated memory; and
5 retrieving said test data at a later time.

1 11. The method of claim 10, wherein said memory test data is a bitmap.

1 12. The method of claim 10, wherein said memory test data is fail data generated
2 from a bitmap.

1 13. The method of claim 12, further including ORing additional test data with
2 said test data already stored in said designated memory.

1 14. The method of claim 10, further including compressing said data before
2 storing said data in said designated memory.

1 15. The method of claim 14, further including decompressing said data after
2 retrieving said data from said designated memory.

1 16. A method of testing a semiconductor device having a memory, comprising:
2 providing a designated memory;
3 performing an LBIST on a device logic function to generate a set of
4 LBIST signatures;
5 storing said LBIST signatures in said designated memory; and
6 retrieving said LBIST signatures at a later time.

1 17. The method of claim 16, further including compressing said data before
2 storing said data in said designated memory.

1 18. The method of claim 17, further including decompressing said data after
2 retrieving said data from said designated memory.

1 19. The method of claim 16, wherein said LBIST is run on every group of N
patterns, each group of N patterns having a cumulative fail signature.

1 20. The method of claim 19, further including :
2 identifying a failing group of N patterns;
3 performing a second LBIST on said device logic functions using every LBIST
4 pattern from said group of N patterns; and
5 identifying every failing pattern in said group of N patterns.

1 21. A method of testing a function of a semiconductor device having a memory,
2 comprising:
3 providing a designated memory;
4 performing a first test using a test pattern in a first corner of the test
5 specification of said function of said semiconductor device ;
6 storing the result of said first test in said designated memory;
7 performing a second test using said test pattern in a second corner of the
8 test specification of said function of said semiconductor device;
9 retrieving said first test result from said designated memory; and
10 comparing said first test result with said second test result.

1 22. The method of claim 21, further including generating a pass signal in response
2 to said first test result matching said second test result and generating a fail signal in
3 response to said first test result not matching said second test result.

1 23. The method of claim 21 further including compressing said first test result
2 before storing said first test result in said designated memory and decompressing said
3 first test result after retrieving said first test result from said designated memory but
4 before comparing said first test result to said second test result.

1 24. The method of claim 21 wherein said designated memory contains at least as
2 many bits as there are latches in said function of said semiconductor device.

1 25. The method of claim 24, wherein said designated memory has a word length
2 at least equal to the number of scan chains in said function of said semiconductor device.

1 26. A semiconductor device comprising:
2 a memory;
3 an ABIST engine adapted to test said memory; and
4 an interface adapted to send test data to and receive test data from a
5 designated portion of said memory.

1 27. The semiconductor device of claim 26, wherein said interface is an ABIST
2 interface and said test data is bitmap data.

1 28. The semiconductor device of claim 27, wherein said ABIST interface includes
a data compress function and said ABIST engine includes a data decompress function.

1 29. The semiconductor device of claim 26, further including an LBIST engine
2 adapted to test device logic functions and wherein said interface is an LBIST interface
3 and said test data comprises LBIST patterns.

1 30. The semiconductor device of claim 29, wherein said LBIST interface includes
2 a data compress function and said LBIST engine includes a data decompress function.

1 31. The semiconductor device of claim 26, further including a corner compare
2 function adapted to compare the results of a test pattern run in two corners of the test
3 specification of said semiconductor device and wherein said interface is a corner
4 interface and said test data is the result of a first corner test.

1 32. The semiconductor device of claim 31, wherein said corner interface includes
2 a data compress function and said corner compare includes a data decompress function.

1 33. The semiconductor device of claim 26, further including a repair function
adapted to soft repair said designated portion of said memory segment.